

e-post: jing.li@su.se

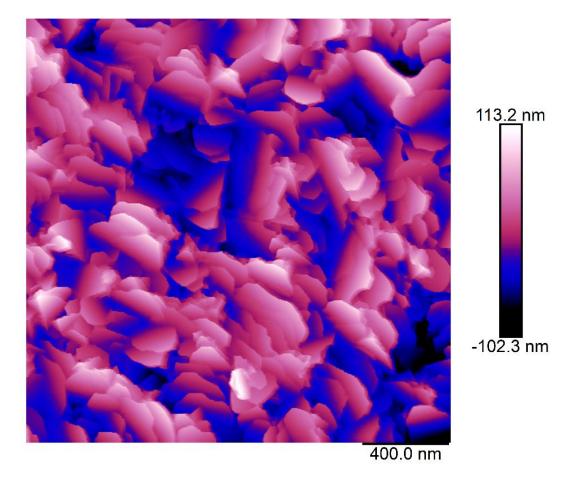


Figure caption Atomic force microscopy (AFM) image of a Ti rough sample acquired using a Bruker Multimode AFM in PeakForce Tapping mode. An AFM probe with a tip radius of \sim 2 nm and a spring constant of 0.4 N/m was used.

The image reveals detailed nanostructures of the Ti surface.

Image taken by Dr. Jing Li, jing.li@su.se